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Substitute for form 1449/PTO				<b>Complete if Known</b>	
				Application Number	10/554,059-Conf. #7920
				Filing Date	September 1, 2006
				First Named Inventor	Akira Otomo
				Art Unit	1792
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	32011-224744

<b>U.S. PATENT DOCUMENTS</b>					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
AA*	US-6,537,800-B1	03-25-2003	Karube et al.	Corresponding to WO99/46588	

<b>FOREIGN PATENT DOCUMENTS</b>					
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)			
BD	WO-99/46588	09-16-1999	Shimizu, Hatsuhi et al.	Corresponds to US 6,537,800	
BE	JP-2001-277200	10-09-2001	Toshiba Corp.		

Examiner Signature	Date Considered
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. \* CITE NO.: Those application(s) which are marked with an single asterisk (\*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

<b>NON PATENT LITERATURE DOCUMENTS</b>					
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
	CU	A. Majumdar, et al., "Nanometer-scale lithography using the atomic force microscope" Appl. Phys. Lett, November 9, 1992, Vol. 61, No. 19, pp. 2293-2295			
	CV	Japanese Office Action in Japan Patent Application No.: 2005-505876, dated June 16, 2009, with English language translation			

Examiner Signature	/Robert S. Walters Jr./	Date Considered	12/02/2009
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